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6. List of Patents and Publications for Applicant's

INFORMATION DISCLOSURE STATEMENT

(Use several sheets if necessary)

Applicant

Cowles and Bollinger

Filing Date:

July 17, 2003

Group:

1743

U.S. Patent Documents

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Foreign Patent Documents

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Other Art

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U.S. Patent Documents

Exam. Init.	Ref. Des.	Document Number	Date	Name	Class	Sub Class	Filing Date of App.

Foreign Patent Documents

Exam. Init.	Ref. Des.	Document Number	Date	Country	Class	Sub Class	Translation Yes/No

Other Art (Including Author, Title, Date Pertinent Pages, Etc.)

Exam. Init.	Ref. Des.	Citation
MW	C1	Chen <i>et al.</i> , "Spectrophotometric Determination of Trace and Ultratrace Levels of Boron in Silicon and Chlorosilane Samples," <i>Fresenius J. Anal. Chem.</i> , 340:357-362, 1991.
MW	C2	Cowles and Bollinger, "Point-of-Use Sampling and Metal Analysis for Trichlorosilane," <i>SEMI Technical Symposium (STS): Innovations in Semiconductor Manufacturing</i> , July 2002.
MW	C3	Stolyarova and Orlova, "Trichlorosilane and Silicon Tetrachloride Sample Preparation for Trace Boron, Phosphorus, and Arsenic Determination," <i>J. Anal. Chem.</i> , 50(2):130-134, 1995.
MW	C4	Wei and Yang, "Determination of Phosphorus and Arsenic in Trichlorosilane by Electrothermal Vaporization-Inductively Coupled Plasma Mass Spectrometry with Prior Concentration by Cuprous Chloride," <i>Fresenius J. Anal. Chem.</i> , 353:167-170, 1995.
MW	C5	Presentation of POU Sampling and Metal Analysis of Trichlorosilane at SEMI Semiconductor Equipment and Materials International, July 2002.

EXAMINER:

/Maureen Wallenhorst/ (11/29/2006)

DATE CONSIDERED:

EXAMINER: INITIAL IF REFERENCE CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED. INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.

INFORMATION DISCLOSURE STATEMENT — PTO-1449 (MODIFIED)